

Welcome to E-XFL.COM

What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M3
Core Size	32-Bit Single-Core
Speed	80MHz
Connectivity	I ² C, SPI, UART/USART
Peripherals	DMA, POR, PWM, WDT
Number of I/O	40
Program Memory Size	256KB (128K x 8 x 2)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	32K x 8
Voltage - Supply (Vcc/Vdd)	2.9V ~ 3.6V
Data Converters	A/D 16x14b; D/A 12x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C
Mounting Type	Surface Mount
Package / Case	96-TFBGA, CSPBGA
Supplier Device Package	96-CSPBGA (6x6)
Purchase URL	https://www.e-xfl.com/product-detail/analog-devices/aducm320bbc

ADUCM320* PRODUCT PAGE QUICK LINKS

Last Content Update: 02/23/2017

COMPARABLE PARTS

View a parametric search of comparable parts.

EVALUATION KITS

- ADuCM320 Evaluation Board

DOCUMENTATION

Application Notes

- AN-1310: Flash Programming via MDIO—Protocol Type 8
- AN-1322: ADuCM320 Code Execution Speed

Data Sheet

- ADuCM320: Precision Analog Microcontroller, 14-Bit Analog I/O with MDIO Interface, ARM Cortex-M3 Data Sheet

User Guides

- UG-498: ADuCM320 Hardware Reference Manual
- UG-692: ADuCM320 Development Systems Getting Started Tutorial

DESIGN RESOURCES

- ADuCM320 Material Declaration
- PCN-PDN Information
- Quality And Reliability
- Symbols and Footprints

DISCUSSIONS

View all ADuCM320 EngineerZone Discussions.

SAMPLE AND BUY

Visit the product page to see pricing options.

TECHNICAL SUPPORT

Submit a technical question or find your regional support number.

DOCUMENT FEEDBACK

Submit feedback for this data sheet.

TABLE OF CONTENTS

Features	1	Absolute Maximum Ratings	21
Applications.....	1	ESD Caution.....	21
Revision History	2	Pin Configuration and Function Descriptions.....	22
Functional Block Diagram	3	Typical Performance Characteristics	27
General Description	4	Recommended Circuit and Component Values	28
Specifications.....	5	Packaging and Ordering Information	30
Microcontroller Electrical Specifications.....	5	Outline Dimensions.....	30
Timing Specifications	15	Ordering Guide	30

REVISION HISTORY

10/15—Rev. B to Rev. C

Change to Features Section	1
Added Table 2; Renumbered Sequentially	10
Changes to Table 7 and Figure 5.....	18
Changes to Table 8 and Figure 6.....	19
Change to Table 10	21
Changes to Figure 14.....	27
Changes to Ordering Guide	30

3/15—Rev. A to Rev. B

Changes to Table 1.....	7
Changes to t_{SHD} and t_{PSU} Parameters, Table 3	10

11/14—Rev. 0 to Rev. A

Changes to Figure 1.....	3
Changes to General Description	4
Changes to Table 1.....	5
Added Timing Specifications Section.....	10
Added Figure 2; Renumbered Sequentially	10
Added Figure 3.....	11
Added Figure 4.....	12
Added Figure 5.....	13
Added Figure 6 and Figure 7.....	14
Changes to Absolute Maximum Ratings Section	15
Changes to Pin C3 and Pin A11 Descriptions.....	17
Changes to Ordering Guide	24

6/14—Revision 0: Initial Version

FUNCTIONAL BLOCK DIAGRAM

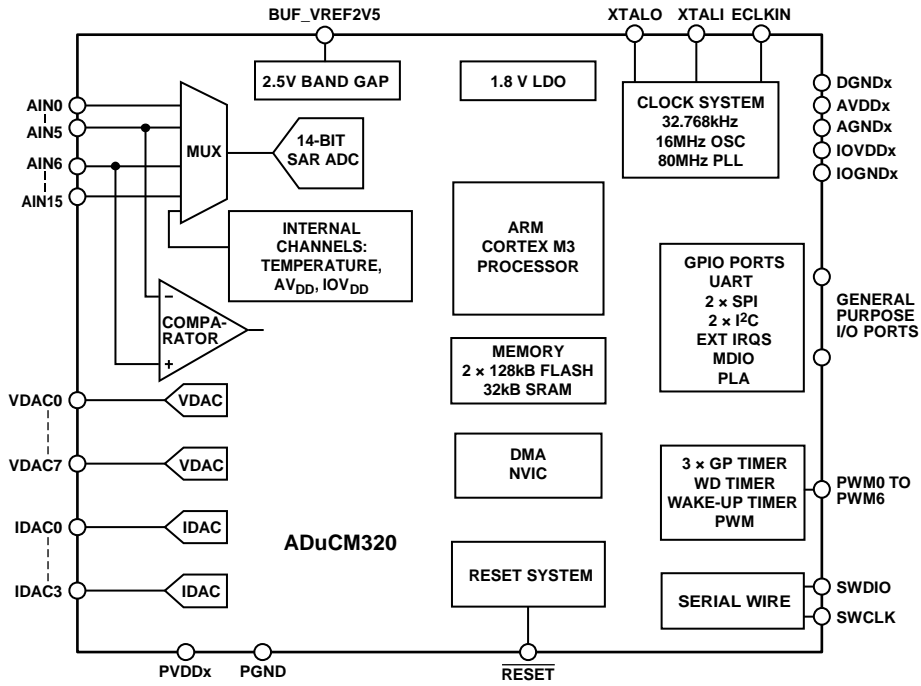


Figure 1.

12272-001

GENERAL DESCRIPTION

The [ADuCM320](#) is a fully integrated single package device that incorporates high performance analog peripherals together with digital peripherals controlled by an 80 MHz ARM Cortex-M3 processor and integral flash for code and data.

The ADC on the [ADuCM320](#) provides 14-bit, 1 MSPS data acquisition on up to 16 input pins that can be programmed for single-ended or differential operation. The voltage at the IDAC output pins can also be measured by the ADC, which is useful for controlling the power consumption of the current DACs. Additionally, chip temperature and supply voltages can be measured.

The ADC input voltage is 0 V to VREF. A sequencer is provided, which allows a user to select a set of ADC channels to be measured in sequence without software involvement during the sequence. The sequence can optionally repeat automatically at a user selectable rate.

Up to eight VDACs are provided with output ranges that are programmable to one of two voltage ranges.

Four IDAC sources are provided. The output currents are programmable with ranges of 0 mA to 150 mA. A low drift band gap reference and voltage comparator completes the analog input peripheral set.

The [ADuCM320](#) can be configured so that the digital and analog outputs will retain their output voltages and currents through a watchdog or software reset sequence. Thus, a product can remain functional even while the [ADuCM320](#) is resetting itself.

The [ADuCM320](#) has a low power ARM Cortex-M3 processor and a 32-bit RISC machine that offers up to 100 MIPS peak performance. Also integrated on chip are 2 × 128 kB Flash/EE memory and 32 kB of SRAM. The flash comprises two separate 128 kB blocks supporting execution from one flash block and simultaneous writing/erasing of the other flash block.

The [ADuCM320](#) operates from an on-chip oscillator or a 16 MHz external crystal and a PLL at 80 MHz. This clock can

optionally be divided down to reduce current consumption. Additional low power modes can be set via software. In normal operating mode, the [ADuCM320](#) digital core consumes about 300 μ A per MHz.

The device includes an MDIO interface capable of operating at up to 4 MHz. The capability to simultaneously execute from one flash block and write/erase the other flash block makes the [ADuCM320](#) ideal for 10G, 40G, and 100G optical applications. User programming is eased by incorporating PHYADR and DEVADD hardware comparators. In addition, the nonerasable kernel code plus flags in user flash provide assistance by allowing user code to robustly switch between the two blocks of user flash code and data spaces.

The [ADuCM320](#) integrates a range of on-chip peripherals that can be configured under software control, as required in the application. These peripherals include 1 × UART, 2 × I²C, and 2 × SPI serial input/output communication controllers, GPIO, 32-element programmable logic array, 3 general-purpose timers, plus a wake-up timer and system watchdog timer. A 16-bit PWM with seven output channels is also provided.

GPIO pins on the device power up in high impedance input mode. In output mode, the software chooses between open-drain mode and push-pull mode. The pull-up resistors can be disabled and enabled in software. In GPIO output mode, the inputs can remain enabled to monitor the pins. The GPIO pins can also be programmed to handle digital or analog peripheral signals, in which case the pin characteristics are matched to the specific requirement.

A large support ecosystem is available for the ARM Cortex-M3 processor to ease product development of the [ADuCM320](#). Access is via the ARM serial wire debug port (SW-DP). On-chip factory firmware supports in-circuit serial download via MDIO. These features are incorporated into a low cost QuickStart development system supporting this precision analog microcontroller family.

Parameter	Symbol	Min	Typ	Max	Unit	Test Conditions/Comments
Leakage Current AIN0 to AIN4, AIN6 to AIN15 AIN5			±1.5 ±20		nA nA	Pin shared with comparator
Input Current			±9 ±6 ±4		µA/V µA/V µA/V	At 1 MSPS; buffer off ≤800 kSPS; buffer off 500 kSPS; buffer off; ADCCNVC[25:16] = 0x1E
Input Capacitance			20		pF	During ADC acquisition
ADC INPUT BUFFER ² Voltage Compliance ¹ Input Current		0.15		2.5	V nA	When enabled by software Reduced accuracy below 0.15 V V _{IN} = 0.15 V to 2.5 V, ADC converting
ON-CHIP VOLTAGE REFERENCE Accuracy Reference Temperature Coefficient ¹ Power Supply Rejection Ratio Internal V _{REF} Power-On Time			2.51		V mV ppm/°C dB ms	0.47 µF from VREF_1V2 to AGND4; reference is measured with all ADCs, VDACs, and IDACs enabled T _A = 25°C
PSRR		-34	-15	+4		
EXTERNAL REFERENCE INPUT Range ¹ Input Current		1.8		2.5	V µA	ADC
BUFFERED REFERENCE OUTPUT Output Voltage Accuracy Reference Temperature Coefficient ¹ Output Impedance Load Current ¹			2.504 ±8 -55 -5	+40	V mV µV/°C Ω mA	T _A = 25°C, load = 1.2 mA 100 nF from BUF_VREF2V5 to AGND4 T _A = 25°C
VDAC CHANNEL SPECIFICATIONS DC Accuracy ¹ Resolution ¹ Relative Accuracy ⁴ Differential Nonlinearity ⁴ Offset Error Drift Gain Error ⁵ Drift Mismatch Analog Outputs Output Voltage Range 1 ¹ Output Voltage Range 2 ¹ Output Impedance DAC AC Characteristics	INL DNL	12 12 -0.99	±4	+1	Bits Bits LSB LSB mV µV/°C % % ppm/°C % V V Ω	R _L = 5 kΩ, C _L = 100 pF ³ 1 LSB = 2.5 V/2 ¹² Number of data bits 1 LSB = 2.5 V/2 ¹² Guaranteed monotonic, 1 LSB = 2.5 V/2 ¹² 2.5 V internal reference, DAC Output Code 0 0 V to internal V _{REF} range 0 V to AVDD range Excluding reference drift % of full scale on DAC0
Output Settling Time Glitch Energy			10 ±20		µs nV-sec	Settled to ±1 LSB 1 LSB change when the maximum number of bits changes simultaneously in the DACxDAT register
IDAC CHANNEL SPECIFICATIONS Resolution ¹ Full-Scale Output ¹ Supply Voltage Each Channel ¹ Output Compliance Range IDAC0, IDAC1 IDAC2, IDAC3		14 1.8 0.4 0.4	150	2.5	Bits mA V V V	Combination of overlapping 11 bits and 5 bits Separate PVDDx supply for each channel See Figure 11 See Figure 11
				PVDDx – 400 mV PVDDx – 250 mV		

Parameter	Symbol	Min	Typ	Max	Unit	Test Conditions/Comments
Full-Scale Error						IDAC set to 85% of full scale
IDAC0, IDAC1				±0.75	%	25°C to 105°C range
IDAC2, IDAC3				±3.5	%	–40°C to +105°C range
Full-Scale Error Drift				±0.75	%	–40°C to +105°C range
IDAC0, IDAC1						Internal V _{REF}
–40°C to +85°C			25		µA/°C	
25°C to 85°C			5		µA/°C	
IDAC2, IDAC3			2		µA/°C	Internal V _{REF}
Integral Nonlinearity	INL		±3	±6	LSB	1 LSB = 150 mA/2 ¹¹
Differential Nonlinearity	DNL	–0.99		+1.5	LSB	Guaranteed 11-bit monotonic, 1 LSB = 150 mA/2 ¹¹
Zero-Scale Error			±50		µA	
Zero-Scale Error Drift						
IDAC0, IDAC1			±300		nA/°C	
IDAC2, IDAC3			±800		nA/°C	
Noise Current			2		µA	IDACxCON[5:2] = 0
Pull-Down Current		–220	–165	–100	µA	When enabled
Settling Time						IDACxCON[5:2] = 0
To 0.1%			100		µs	±4 mA change from midscale
To 1%			50		µs	±4 mA change from midscale
Full Scale to 0 mA			20		µs	Pull-down enabled
Overheat Shutdown			135		°C	Junction temperature
PVDD ACPSRR						IDACxCON[5:2] = 0
100 Hz			51		dB	
1 kHz			45		dB	
10 kHz			25		dB	
100 kHz			10		dB	
COMPARATOR						
Input						
Offset Voltage			±10		mV	
Bias Current			1		nA	
Voltage Range ¹		AGNDx		AVDDx – 1.2	V	
Capacitance			7		pF	
Hysteresis ¹		8.5		15	mV	When enabled in software
Response Time			7		µs	AFECOMP[2:1] = 0
TEMPERATURE SENSOR						
Resolution			0.5		°C	Indicates die temperature, see Figure 9
Accuracy ¹		1.34		1.43	V	When precision calibrated by the user ⁶ ADC measured voltage for temperature sensor channel without calibration, T = 25°C
POWER-ON RESET						
External Reset Minimum Pulse Width ¹	POR	1.5	2.85	2.9	µs	Minimum pulse width required on external reset pin to trigger a reset sequence
WATCHDOG TIMER						
Timeout Period	WDT		32		sec	Default at power-up
FLASH/EE MEMORY						
Endurance ¹		10,000			Cycles	
Data Retention ¹		20			Years	T _J = 85°C

Parameter	Symbol	Min	Typ	Max	Unit	Test Conditions/Comments
DIGITAL INPUTS						
Input Leakage Current						
Logic 1 GPIO			1		nA	$V_{IH} = V_{DD}$, pull-up resistor disabled
Logic 0 GPIO			10		nA	$V_{IL} = 0\text{ V}$, pull-up resistor disabled
PRTADDRx						
Input Leakage Current			16		μA	$V_{IN} = 0$ to 1.8 V, due to weak pull-up resistors to 1.8 V
Input Voltage		0.84		1.5	V	External resistor $91\text{ k}\Omega \pm 1\%$ to ground, range for CFP MSA high ¹
Input Capacitance, All Pins Except MCK, MDIO, PRTADDRx, and XTALx			10		pF	
Input Capacitance						
MCK, PRTADDRx			6.5		pF	
MDIO			8.5		pF	
Pin Capacitance						
XTALI			5		pF	
XTALO			5		pF	
LOGIC INPUTS						
GPIO Input Voltage						
Low	V_{INL}			$0.25 \times IOVDDx$	V	
High	V_{INH}	$0.58 \times IOVDDx$			V	
MDIO						
PRTADDRx Input Voltage						
Low	V_{INL}			0.36	V	
High	V_{INH}	0.84			V	
MCK, MDIO Input Voltage						
Low	V_{INL}			0.36	V	
High	V_{INH}	0.84			V	
XTALI Input Voltage						
Low	V_{INL}		1.1		V	
High	V_{INH}		1.7		V	
Pull-Up Current		30		120	μA	$V_{IN} = 0\text{ V}$, see Figure 10
Pull-Down Current		30		100	μA	$V_{IN} = 3.3\text{ V}$, see Figure 10
LOGIC OUTPUTS						
GPIO Output Voltage⁷						
High	V_{OH}	$IOVDDx - 0.4$			V	$I_{SOURCE} = 2\text{ mA}$
Low	V_{OL}			0.4	V	$I_{SINK} = 2\text{ mA}$
GPIO Short-Circuit Current ¹			11		mA	See Figure 13
MDIO						
Output Voltage						
High	V_{OH}	1.0			V	$I_{SOURCE} = 4\text{ mA}$
Low	V_{OL}			0.2	V	$I_{SINK} = 4\text{ mA}$
Delay Time				100	ns	MCK to MDIO out
OSCILLATORS						
Internal System Oscillator						
Accuracy			± 0.5	± 3	MHz	
System PLL			80		MHz	Main system clock
External Crystal Oscillator						
			16		MHz	Can be selected in place of internal oscillator
32 kHz Internal Oscillator						
Accuracy			32.768		kHz	Use for watchdog
Accuracy			± 5	± 20	%	
External Clock		0.05		80	MHz	Can be selected in place of PLL
START-UP TIME						
At Power-On			40		ms	Processor clock = 80 MHz
After Other Reset			1.5		ms	POR to first user code execution
From All Power-Down Modes			1.25		μs	Reset to first user code execution

Parameter	Symbol	Min	Typ	Max	Unit	Test Conditions/Comments
PROGRAMMABLE LOGIC ARRAY	PLA					
Propagation Delay			17		ns	From input pin to output pin
Pin Element			1.5		ns	Per PLA cell
EXTERNAL INTERRUPTS						
Pulse Width ¹						
Level Triggered		7			ns	
Edge Triggered		1			ns	
POWER REQUIREMENTS ⁸						
Power Supply Voltage Range						
AVDDx to AGNDx and IOVDDx to DGNDx ¹		2.9	3.3	3.6	V	
Analog Power Supply Currents						
AVDDx Current			6.3		mA	Analog peripherals in idle mode
Digital Power Supply Current						
IOVDDx Current in Normal Mode			4		mA	All GPIO pull-up resistors enabled
VDDx Current						
Normal Mode ⁹			29		mA	CD = 0 (80 MHz clock) executing typical code
			20		mA	CD = 1 executing typical code
			10		mA	CD = 7 executing typical code
CORE_SLEEP Mode ⁹			16		mA	
SYS_SLEEP Mode ⁹			8		mA	
Hibernate Mode ⁹			6.6		mA	
Additional Power Supply Currents						
ADC			4.1		mA	Continuously converting at 100 kSPS
ADC Input Buffer			4.0		mA	Both buffers enabled
IDAC			16.5		mA	Excluding load current
DAC			340		μA	Per powered up DAC, excluding load current
Total Supply Current		35	40	45	mA	VDD1, IOVDDx, AVDDx connected together; condition when entering user code: peripheral clocks on, peripherals idle, no load currents
Thermal Performance						
Impedance Junction to Ambient			45		°C/W	JEDEC 2S2P

¹ These numbers are not production tested but are guaranteed by design and/or characterization data at production release.

² Enabling the input buffer changes the ADC input characteristics as described in this subsection.

³ The data in this section also applies for a load of $R_L = 1 \text{ k}\Omega$ and $C_L = 100 \text{ pF}$ to GND but only for 0 V to 2.5 V. However, this is not production tested.

⁴ DAC linearity is calculated using a reduced code range of 100 to 3900.

⁵ DAC gain error is calculated using a reduced code range of 100 to an internal $2.5 \text{ V } V_{REF}$.

⁶ Due to self heating, internal temperature measurements cannot be used to predict external temperatures. This value is only relevant after user calibration and only for internal and external conditions identical to those at calibration.

⁷ The average current from all GPIO pins must not exceed 3 mA per pin.

⁸ Power figures exclude any load currents to external circuits.

⁹ See the ADuCM320 reference manual, *How to Set up and Use the ADuCM320*.

AVDD = IOVDD = VDD1 = 2.9 V to 3.6 V maximum difference between supplies = 0.3 V, VREF = 2.5 V internal reference, $f_{\text{CORE}} = 80$ MHz, $T_A = -40^\circ\text{C}$ to $+105^\circ\text{C}$, unless otherwise noted. PVDDx for IDACs = 1.8 V to 2.5 V. Power-up sequence must be VDD1, IOVDDx, AVDDx, and then PVDDx, but no delays in the sequence are required.

Table 2.

Parameter	Symbol	Min	Typ	Max	Unit	Test Conditions/Comments
ADC BASIC SPECIFICATIONS						
ADC Power-Up Time			5		μs	Single-ended mode, unless otherwise stated
Data Rate	f_{SAMPLE}			1	MSPS	
DC Accuracy ¹		14			Bits	1 LSB = $2.5 \text{ V}/2^{14}$
Resolution ¹		16			Bits	Number of data bits
Integral Nonlinearity	INL		± 1.75		LSB	2.5 V internal reference; 1 LSB = $2.5 \text{ V}/2^{14}$
			± 1.75		LSB	2.5 V external reference; 1 LSB = $2.5 \text{ V}/2^{14}$
Differential Nonlinearity	DNL	-0.99	± 0.75	+1.5	LSB	2.5 V internal reference; 1 LSB = $2.5 \text{ V}/2^{14}$
			± 0.75		LSB	2.5 V external reference; 1 LSB = $2.5 \text{ V}/2^{14}$
DC Code Distribution			± 3		LSB	ADC input 1.25 V; 1 LSB = $2.5 \text{ V}/2^{14}$
ADC ENDPOINT ERRORS						
Offset Error					μV	Using 2.5 V external reference
Input Buffer Off			± 200		$\mu\text{V}/^\circ\text{C}$	
Drift ¹		-2.25		+1.2	μV	Using 2.5 V external reference
Input Buffer On			-250		$\mu\text{V}/^\circ\text{C}$	
Drift ¹		-3		+2	$\mu\text{V}/^\circ\text{C}$	Matching compared to AIN8
Match			± 1		LSB	
Full-Scale Error					μV	Full-scale error drift minus offset error drift
Input Buffer Off			± 400		$\mu\text{V}/^\circ\text{C}$	
Gain Drift ¹		-4.3		+2	μV	Full-scale error drift minus offset error drift
Input Buffer On			-350		$\mu\text{V}/^\circ\text{C}$	
Gain Drift ¹		-4.5		+3	$\mu\text{V}/^\circ\text{C}$	Full-scale error drift minus offset error drift
Match			± 1		LSB	
ADC DYNAMIC PERFORMANCE						
Signal-to-Noise Ratio	SNR					$f_{\text{IN}} = 665.25$ Hz sine wave, $f_{\text{SAMPLE}} = 100$ kSPS; input filter = 15Ω , 2 nF Includes distortion and noise components
Input Buffer						
Disabled			80		dB	Measured on adjacent channels
Enabled			74		dB	
Total Harmonic Distortion	THD					Measured on adjacent channels
Input Buffer						
Disabled			-86		dB	Measured on adjacent channels
Enabled			-83		dB	
Peak Harmonic or Spurious Noise			-88		dB	Measured on adjacent channels
Channel-to-Channel Crosstalk			-90		dB	
ADC INPUT						
Input Voltage Ranges						Input buffer not enabled
Single-Ended Mode ¹		AGND4		VREF		Voltage between differential pins
Differential Mode ¹		-VREF		+VREF	V	
Compliance ¹		AGND4		AVDD4	V	
Common Mode ¹		0.9		1.6	V	

Parameter	Symbol	Min	Typ	Max	Unit	Test Conditions/Comments
Full-Scale Error IDAC0, IDAC1				±0.75	%	IDAC set to 85% of full scale 25°C to 105°C range
				±3.5	%	
IDAC2, IDAC3				±0.75	%	
Full-Scale Error Drift IDAC0, IDAC1			25		µA/°C	Internal V _{REF}
–40°C to 105°C			5		µA/°C	
25°C to 105°C			2		µA/°C	Internal V _{REF}
IDAC2, IDAC3						
Integral Nonlinearity	INL		±3	±6	LSB	1 LSB = 150 mA/2 ¹¹
Differential Nonlinearity	DNL	–0.99		+1.5	LSB	Guaranteed 11-bit monotonic, 1 LSB = 150 mA/2 ¹¹
Zero-Scale Error			±50		µA	
Zero-Scale Error Drift IDAC0, IDAC1			±300		nA/°C	
IDAC2, IDAC3			±800		nA/°C	
Noise Current			2		µA	IDACxCON[5:2] = 0
Pull-Down Current		–220	–165	–100	µA	When enabled
Settling Time						IDACxCON[5:2] = 0
To 0.1%			100		µs	±4 mA change from midscale
To 1%			50		µs	±4 mA change from midscale
Full Scale to 0 mA			20		µs	Pull-down enabled
Overheat Shutdown			135		°C	Junction temperature
PVDD ACPSRR						IDACxCON[5:2] = 0
100 Hz			51		dB	
1 kHz			45		dB	
10 kHz			25		dB	
100 kHz			10		dB	
COMPARATOR						
Input						
Offset Voltage			±10		mV	
Bias Current			1		nA	
Voltage Range ¹		AGNDx		AVDDx – 1.2	V	
Capacitance			7		pF	
Hysteresis ¹		8.5		15	mV	When enabled in software
Response Time			7		µs	AFECOMP[2:1] = 0
TEMPERATURE SENSOR						
Resolution			0.5		°C	Indicates die temperature, see Figure 9
Accuracy ¹		1.34		1.43	V	When precision calibrated by the user ⁶ ADC measured voltage for temperature sensor channel without calibration, T = 25°C
POWER-ON RESET	POR		2.85	2.9	V	
External Reset Minimum Pulse Width ¹		1.5			µs	Minimum pulse width required on external reset pin to trigger a reset sequence
WATCHDOG TIMER	WDT					
Timeout Period			32		sec	Default at power-up
FLASH/EE MEMORY						
Endurance ¹		10,000			Cycles	
Data Retention ¹		20			Years	T _J = 85°C

Parameter	Symbol	Min	Typ	Max	Unit	Test Conditions/Comments
DIGITAL INPUTS						
Input Leakage Current						
Logic 1 GPIO			1		nA	$V_{IH} = V_{DD}$, pull-up resistor disabled
Logic 0 GPIO			10		nA	$V_{IL} = 0\text{ V}$, pull-up resistor disabled
PRTADDRx						
Input Leakage Current			16		μA	$V_{IN} = 0$ to 1.8 V, due to weak pull-up resistors to 1.8 V
Input Voltage		0.84		1.5	V	External resistor $91\text{ k}\Omega \pm 1\%$ to ground, range for CFP MSA high ¹
Input Capacitance, All Pins Except MCK, MDIO, PRTADDRx, and XTALx			10		pF	
Input Capacitance						
MCK, PRTADDRx			6.5		pF	
MDIO			8.5		pF	
Pin Capacitance						
XTALI			5		pF	
XTALO			5		pF	
LOGIC INPUTS						
GPIO Input Voltage						
Low	V_{INL}			$0.25 \times IOVDDx$	V	
High	V_{INH}	$0.58 \times IOVDDx$			V	
MDIO						
PRTADDRx Input Voltage						
Low	V_{INL}			0.36	V	
High	V_{INH}	0.84			V	
MCK, MDIO Input Voltage						
Low	V_{INL}			0.36	V	
High	V_{INH}	0.84			V	
XTALI Input Voltage						
Low	V_{INL}		1.1		V	
High	V_{INH}		1.7		V	
Pull-Up Current		30		120	μA	$V_{IN} = 0\text{ V}$, see Figure 10
Pull-Down Current		30		100	μA	$V_{IN} = 3.3\text{ V}$, see Figure 10
LOGIC OUTPUTS						
GPIO Output Voltage⁷						
High	V_{OH}	$IOVDDx - 0.4$			V	$I_{SOURCE} = 2\text{ mA}$
Low	V_{OL}			0.4	V	$I_{SINK} = 2\text{ mA}$
GPIO Short-Circuit Current ¹			11		mA	See Figure 13
MDIO						
Output Voltage						
High	V_{OH}	1.0			V	$I_{SOURCE} = 4\text{ mA}$
Low	V_{OL}			0.2	V	$I_{SINK} = 4\text{ mA}$
Delay Time				100	ns	MCK to MDIO out
OSCILLATORS						
Internal System Oscillator						
Accuracy			± 0.5	± 3	MHz %	
System PLL			80		MHz	Main system clock
External Crystal Oscillator						
			16		MHz	Can be selected in place of internal oscillator
32 kHz Internal Oscillator						
Accuracy			± 5	± 20	kHz %	Use for watchdog
External Clock		0.05		80	MHz	Can be selected in place of PLL
START-UP TIME						
At Power-On			40		ms	Processor clock = 80 MHz
After Other Reset			1.5		ms	POR to first user code execution
From All Power-Down Modes			1.25		μs	Reset to first user code execution

Parameter	Symbol	Min	Typ	Max	Unit	Test Conditions/Comments
PROGRAMMABLE LOGIC ARRAY	PLA					
Propagation Delay			17		ns	From input pin to output pin
Pin Element			1.5		ns	Per PLA cell
EXTERNAL INTERRUPTS						
Pulse Width ¹						
Level Triggered		7			ns	
Edge Triggered		1			ns	
POWER REQUIREMENTS ⁸						
Power Supply Voltage Range		2.9	3.3	3.6	V	
AVDDx to AGNDx and IOVDDx to DGNDx ¹						
Analog Power Supply Currents			6.3		mA	Analog peripherals in idle mode
AVDDx Current						
Digital Power Supply Current			4		mA	All GPIO pull-up resistors enabled
IOVDDx Current in Normal Mode						
VDDx Current			29		mA	CD = 0 (80 MHz clock) executing typical code
Normal Mode ⁹			20		mA	CD = 1 executing typical code
CORE_SLEEP Mode ⁹			10		mA	CD = 7 executing typical code
SYS_SLEEP Mode ⁹			16		mA	
Hibernate Mode ⁹			8		mA	
Additional Power Supply Currents						
ADC			4.1		mA	Continuously converting at 100 kSPS
ADC Input Buffer			4.0		mA	Both buffers enabled
IDAC			16.5		mA	Excluding load current
DAC			340		μA	Per powered up DAC, excluding load current
Total Supply Current		35	40	45	mA	VDD1, IOVDDx, AVDDx connected together; condition when entering user code: peripheral clocks on, peripherals idle, no load currents
Thermal Performance						
Impedance Junction to Ambient			45		°C/W	JEDEC 2S2P

¹ These numbers are not production tested but are guaranteed by design and/or characterization data at production release.

² Enabling the input buffer changes the ADC input characteristics as described in this subsection.

³ The data in this section also applies for a load of $R_L = 1 \text{ k}\Omega$ and $C_L = 100 \text{ pF}$ to GND but only for 0 V to 2.5 V. However, this is not production tested.

⁴ DAC linearity is calculated using a reduced code range of 100 to 3900.

⁵ DAC gain error is calculated using a reduced code range of 100 to an internal 2.5 V V_{REF} .

⁶ Due to self heating, internal temperature measurements cannot be used to predict external temperatures. This value is only relevant after user calibration and only for internal and external conditions identical to those at calibration.

⁷ The average current from all GPIO pins must not exceed 3 mA per pin.

⁸ Power figures exclude any load currents to external circuits.

⁹ See the ADuCM320 reference manual, [How to Set up and Use the ADuCM320](#)

Table 6. SPI Master Mode Timing (Phase Mode = 0)

Parameter	Description	Min	Typ	Max	Unit
t_{SL}	SCLK low pulse width		$(SPIDIV + 1) \times t_{HCLK}/2$		ns
t_{SH}	SCLK high pulse width		$(SPIDIV + 1) \times t_{HCLK}/2$		ns
t_{DAV}	Data output valid after SCLK edge	0	3		ns
t_{DOSU}	Data output setup before SCLK edge		$\frac{1}{2}$ SCLK		ns
t_{DSU}	Data input setup time before SCLK edge		SCLK		ns
t_{DHD}	Data input hold time after SCLK edge		SCLK		ns
t_{DF}	Data output fall time		25		ns
t_{DR}	Data output rise time		25		ns
t_{SR}	SCLK rise time		20		ns
t_{SF}	SCLK fall time		20		ns

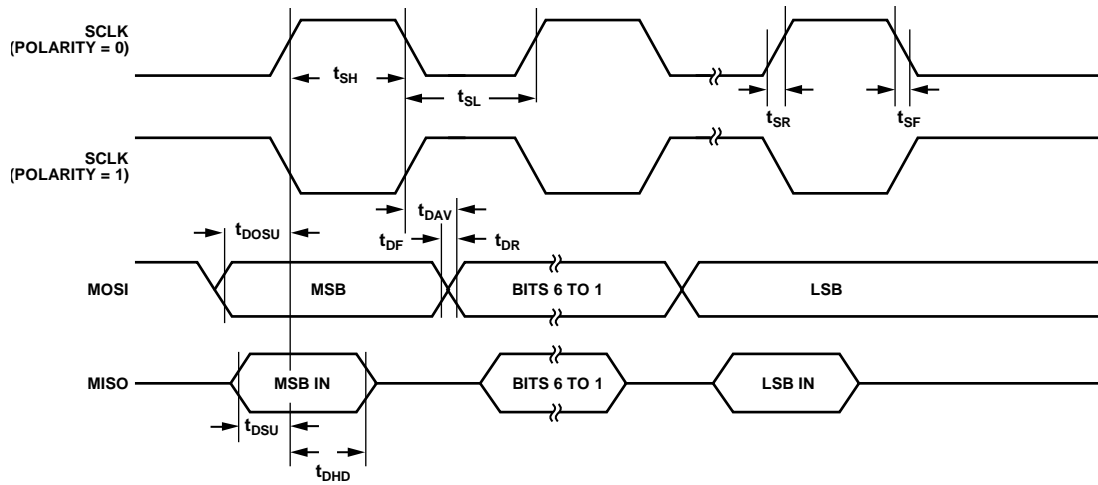


Figure 4. SPI Master Mode Timing (Phase Mode = 0)

12272-004

Table 7. SPI Slave Mode Timing (Phase Mode = 1)

Parameter	Description	Min	Typ	Max	Unit
$t_{\overline{CS}}$	\overline{CS} to SCLK edge	10			ns
$t_{\overline{CSM}}$	\overline{CS} high time between active periods	SCLKx			ns
t_{SL}	SCLK low pulse width		$(SPIDIV + 1) \times t_{HCLK}$		ns
t_{SH}	SCLK high pulse width		$(SPIDIV + 1) \times t_{HCLK}$		ns
t_{DAV}	Data output valid after SCLK edge		20		ns
t_{DSU}	Data input setup time before SCLK edge	10			ns
t_{DHD}	Data input hold time after SCLK edge	10			ns
t_{DF}	Data output fall time		25		ns
t_{DR}	Data output rise time		25		ns
t_{SR}	SCLK rise time	1			ns
t_{SF}	SCLK fall time	1			ns
t_{SFS}	\overline{CS} high after SCLK edge	20			ns

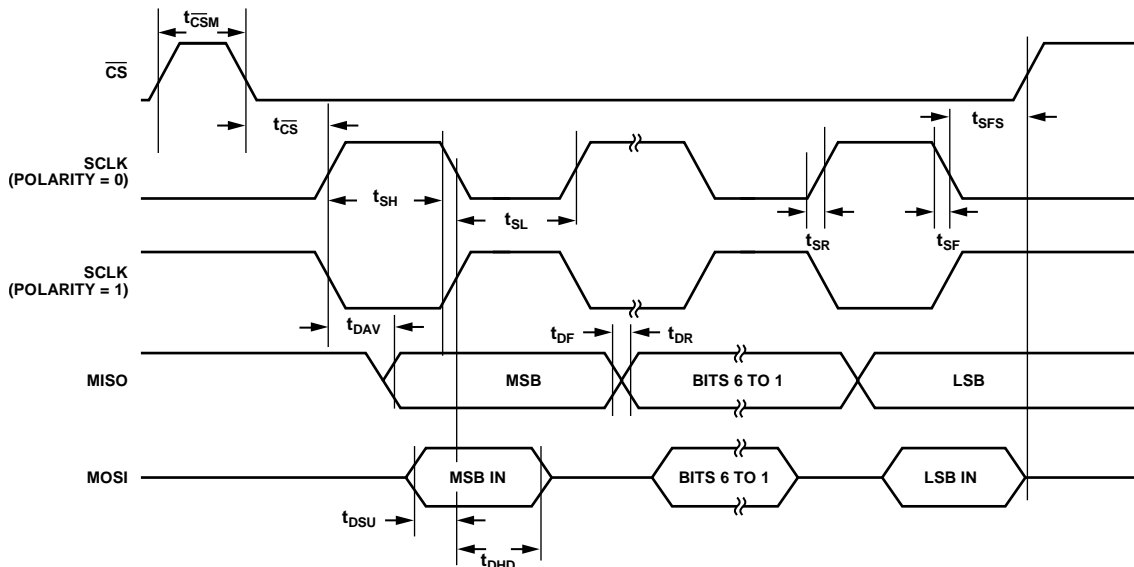


Figure 5. SPI Slave Mode Timing (Phase Mode = 1)

12272-005

Table 8. SPI Slave Mode Timing (Phase Mode = 0)

Parameter	Description	Min	Typ	Max	Unit
$t_{\overline{CS}}$	\overline{CS} to SCLK edge	10			ns
$t_{\overline{CSM}}$	\overline{CS} high time between active periods	SCLKx			ns
t_{SL}	SCLK low pulse width		$(SPIDIV + 1) \times t_{HCLK}$		ns
t_{SH}	SCLK high pulse width		$(SPIDIV + 1) \times t_{HCLK}$		ns
t_{DAV}	Data output valid after SCLK edge		20		ns
t_{DSU}	Data input setup time before SCLK edge	10			ns
t_{DHD}	Data input hold time after SCLK edge	10			ns
t_{DF}	Data output fall time		25		ns
t_{DR}	Data output rise time		25		ns
t_{SR}	SCLK rise time	1			ns
t_{SF}	SCLK fall time	1			ns
t_{DOCS}	Data output valid after \overline{CS} edge	20			ns
t_{SFS}	\overline{CS} high after SCLK edge	10			ns

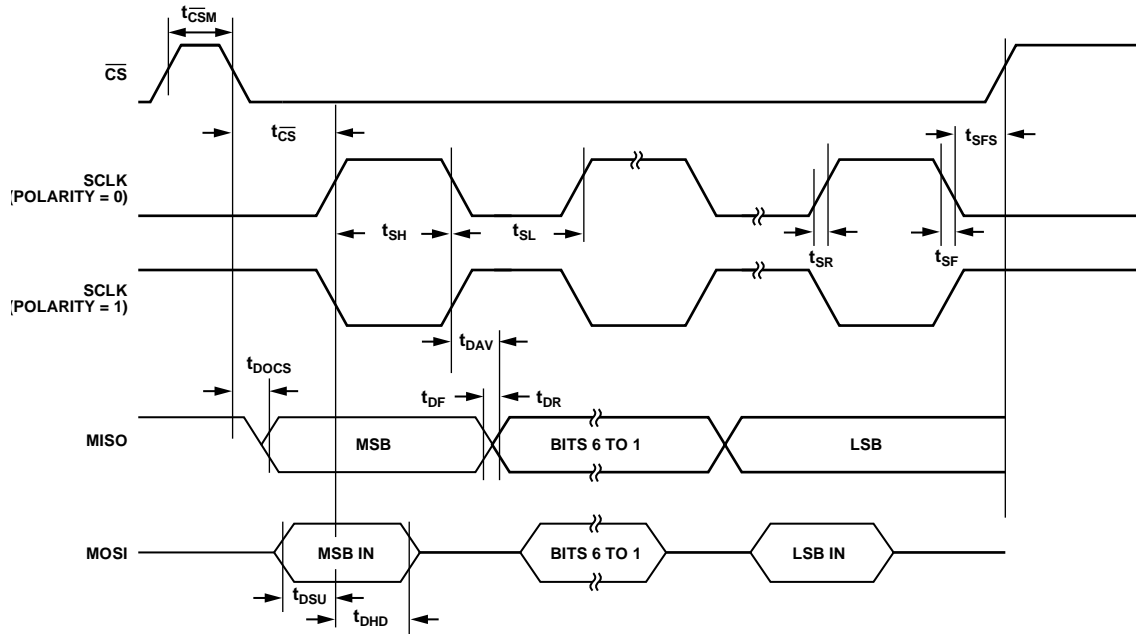


Figure 6. SPI Slave Mode Timing (Phase Mode = 0)

12272-006

Table 9. MDIO vs MDC Timing

Parameter	Description	Min	Typ	Max	Unit
t_{SETUP}	MDIO setup before MCK edge	10			ns
t_{HOLD}	MDIO valid after MCK edge	10			ns
t_{DELAY}	Data output after MCK edge			100	ns

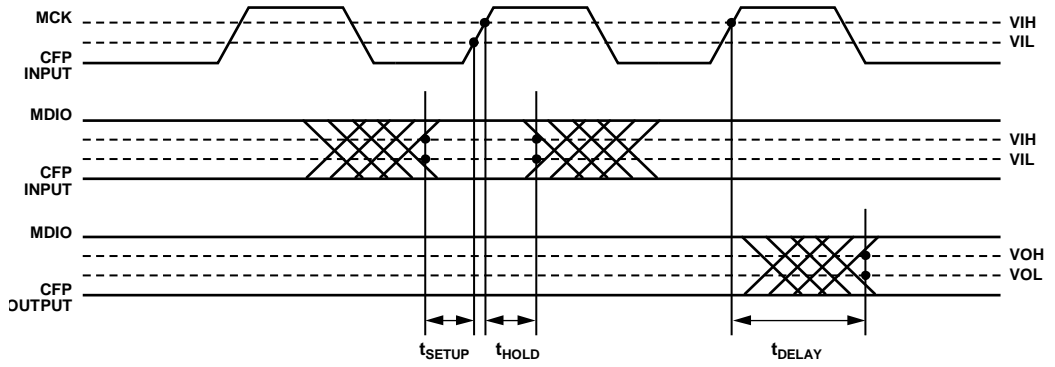


Figure 7. MDIO Timing

12272-007

Pin No.	Mnemonic	Type ¹	Description
D9	P2.4/IRQ5/ADCCONV/PWM6/PLAO[18]	I/O	Digital I/O Port 2.4 (P2.4). External Interrupt 5 (IRQ5). External Input to Start ADC Conversions (ADCCONV). PWM Output 6 (PWM6). Output of PLA Element 18 (PLAO[18]).
F1	P2.6/IRQ7/PLAO[20]	I/O	Digital I/O Port 2.6 (P2.6). External Interrupt 7 (IRQ7). Output of PLA Element 20 (PLAO[20]).
G1	P2.7/IRQ8/PLAO[21]	I/O	Digital I/O Port 2.7 (P2.7). External Interrupt 8 (IRQ8). Output of PLA Element 21 (PLAO[21]).
G3	P3.0/PRTADDR0/PLAI[12]	I/O	Digital I/O Port 3.0 (P3.0). MDIO Port Address Bit 0 (PRTADDR0). See the digital inputs parameter in Table 1 for details. Input to PLA Element 12 (PLAI[12]).
G2	P3.1/PRTADDR1/PLAI[13]	I/O	Digital I/O Port 3.1 (P3.1). MDIO Port Address Bit 1 (PRTADDR1). See the digital inputs parameter in Table 1 for details. Input to PLA Element 13 (PLAI[13]).
D3	P3.2/PRTADDR2/PLAI[14]	I/O	Digital I/O Port 3.2 (P3.2). MDIO Port Address Bit 2 (PRTADDR2). See the digital inputs parameter in Table 1 for details. Input to PLA Element 14 (PLAI[14]).
B3	P3.3/PRTADDR3/PLAI[15]	I/O	Digital I/O Port 3.3 (P3.3). MDIO Port Address Bit 3 (PRTADDR3). See the digital inputs parameter in Table 1 for details. Output of PLA Element 15 (PLAI[15]).
C11	P3.4/PRTADDR4/PLAO[26]	I/O	Digital I/O Port 3.4 (P3.4). MDIO Port Address Bit 4 (PRTADDR4). See the digital inputs parameter in Table 1 for details. Output of PLA Element 26 (PLAO[26]).
H1	P3.5/MCK/PLAO[27]	I/O	Digital I/O Port 3.5 (P3.5). MDIO Clock (MCK) See the digital inputs parameter in Table 1 for more details. Output of PLA Element 27 (PLAO[27]).
H3	MDIO	I/O	MDIO Data.
E9	SWCLK	I	Serial Wire Debug Clock.
E10	SWDIO	I/O	Serial Wire Bidirectional Data.
F11	VREF_1V2	S	1.2 V Reference. This pin cannot be used to source current externally. Connect VREF_1V2 to AGNDx via a 470 nF capacitor.
A11	IREF	AI	IDAC Reference Current. This pin generates the reference current for the IDACs and is set by an external resistor, R _{EXT} . Connect R _{EXT} from IREF to AGND4.
J6	AIN0	AI	Analog Input 0.
J7	AIN1	AI	Analog Input 1.
J8	AIN2	AI	Analog Input 2.
K8	AIN3	AI	Analog Input 3.
L8	AIN4	AI	Analog Input 4.
L9	AIN5	AI	Analog Input 5. AIN5 can be the –ve input for the comparator.
K9	AIN6	AI	Analog Input 6. AIN6 is also the +ve input for the comparator.
J9	AIN7	AI	Analog Input 7.
L10	AIN8/P4.2	AI/I/O	Analog Input 8 (AIN8). Digital I/O Port 4.2 (P4.2).
K10	AIN9/P4.3	AI/I/O	Analog Input 9 (AIN9). Digital I/O Port 4.3 (P4.3).
J10	AIN10	AI	Analog Input 10.

Pin No.	Mnemonic	Type ¹	Description
D11	IOVDD2	S	3.3 V GPIO Supply and Interdie Communications.
J1	IOVDD3	S	3.3 V GPIO Supply.
C1	IOGND1	S	Ground for IOVDD1.
E11	IOGND2	S	Ground for IOVDD2.
K1	IOGND3	S	Ground for IOVDD3 and Interdie Communications.
J5	AGND1	S	Analog Ground for VDD1.
K7	AGND2	S	ESD Ground for Pad Ring.
L7	AGND3	S	Ground for AVDD3.
H11	AGND4	S	Ground for AVDD4, AVDD_REG0, and AVDD_REG1.
K6	VDD1	S	3.3 V Supply for Digital Die.
L6	AVDD3	S	VDAC and IDAC Supply (3.3 V).
G11	AVDD4	S	ADC Supply (3.3 V).
L11	ADC_REFN	AO/A	Decoupling Capacitor Connection for ADC Reference Buffer. Connect this pin to AGND4.
K11	ADC_REFP	AO/A	Decoupling Capacitor Connection for ADC Reference Buffer. Connect this pin to a 4.7 μ F capacitor to the ADC_REFN pin. ADC_REFP can be overdriven by an external reference.
H2	XTALO	O	Output from the Crystal Oscillator Inverter. When not using an external crystal, leave XTALO unconnected.
J2	XTALI	I	Input to the Crystal Oscillator Inverter and Input to the Internal Clock Generator Circuits. When not using an external crystal, connect XTALI to DGND.

¹ AI is analog input, AO is analog output, I is digital input, O is digital output, S is supply.

TYPICAL PERFORMANCE CHARACTERISTICS

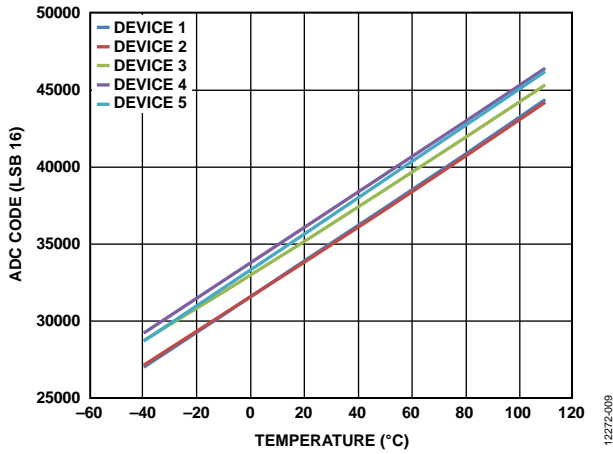


Figure 9. Typical Temperature Measurement vs. Internal Temperature ($V_{DD} = 3.3\text{ V}$, 50 kSPS)

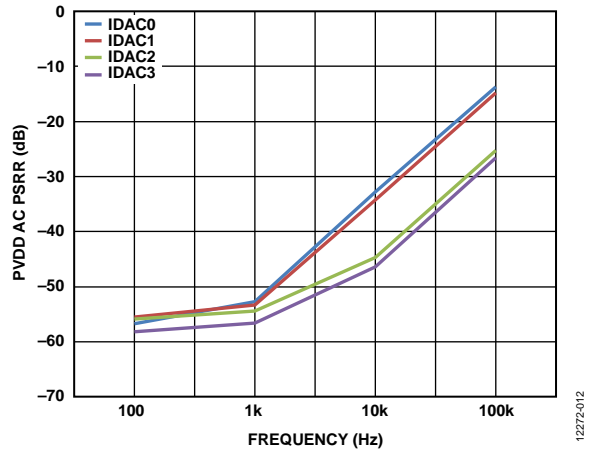


Figure 12. Typical PVDD AC PSRR vs. Frequency

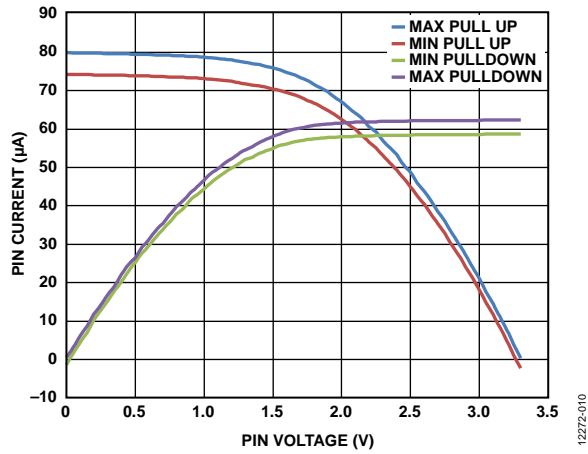


Figure 10. Typical Pull-Up/Pull-Down Pin Current vs. Pin Voltage ($V_{DD} = 3.3\text{ V}$, 25°C)

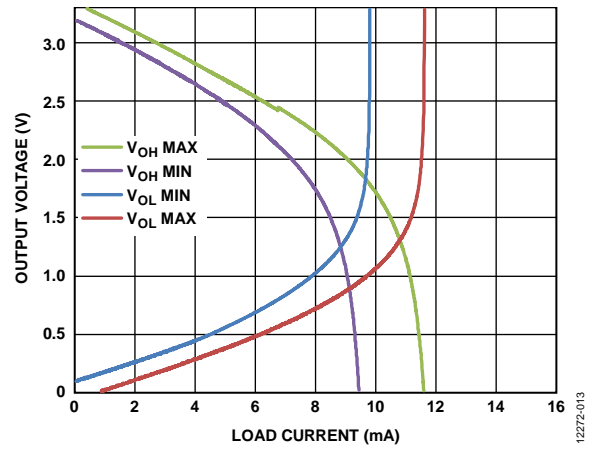


Figure 13. Typical Output Voltage vs. Load Current

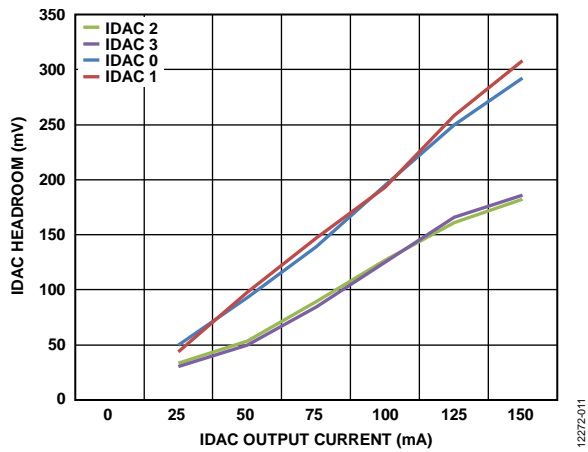


Figure 11. Typical IDAC Headroom vs. IDAC Output Current

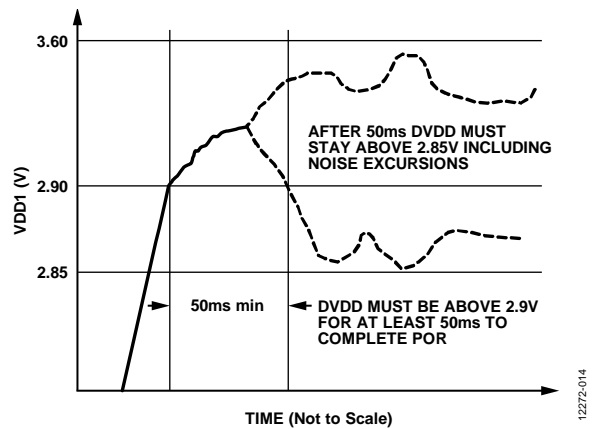


Figure 14. VDD1 Power-On Requirements

RECOMMENDED CIRCUIT AND COMPONENT VALUES

Figure 15 shows a typical connection diagram for the [ADuCM320](#).

Supplies and regulators must be adequately decoupled with capacitors connected between the AVDDx, PVDDx, DVDD_x, AVDD_REGx, IOVDDx, and VDD1 balls and their associated GND balls (AGNDx, PGND, IOGNDx, and DGNDx). Table 11 indicates which ground balls are paired with which supply balls.

There are four digital supply balls, IOVDD1, IOVDD2, IOVDD3, and VDD1. Decouple these balls with a 100 nF capacitor placed as near as possible to each of the four balls and their associated GND balls (IOGNDx and AGND1, respectively). In addition, place a 10 μ F capacitor conveniently near to these balls.

Similarly, the analog supply pins, AVDD3 and AVDD4, each require a 100 nF capacitor placed as near as possible to each ball and its associated AGNDx ball, and place a 10 μ F capacitor conveniently near to these balls.

The IDACs source their output currents from the PVDDx supply balls. Each PVDDx supply ball must have a 100 nF capacitor near to each ball and their associated GND balls (PGND). In addition, place at least one 10 μ F capacitor at the source of the PVDDx supply.

The IDAC output filters depend on a 10 nF capacitor being placed between the CDAMPx and PVDDx.

The ADC reference requires a 4.7 μ F capacitor placed between ADC_REFP and ADC_REFN and located as near as possible to each ball. ADC_REFN must be connected directly to AGND4.

The [ADuCM320](#) contains four internal regulators. These regulators require external decoupling capacitors. The DVDD_1V8 and DVDD_2V5 balls each require a 470 nF capacitor to DGND1 and IOGND3, respectively. AVDD_REG0 and AVDD_REG1 each require a decoupling capacitor to AGND4.

To generate an accurate and low drift reference current, connect the IREF ball to AGND4 via a low ppm 3.16 k Ω resistor.

Take care in the layout to ensure that currents flowing from the ground end of each decoupling capacitor to its associated ground ball share as little track as possible with other ground currents on the printed circuit board.